

<p><i>Notice of References Cited</i></p>	<p>Application/Control No. 10/531,759</p>	<p>Applicant(s)/Patent Under Reexamination FRANKLIN ET AL.</p>	
	<p>Examiner Kianni C. Kaveh</p>	<p>Art Unit 2883</p>	<p>Page 1 of 1</p>

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